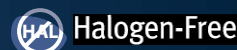
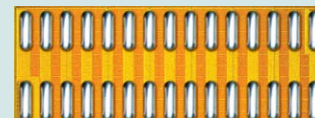


## EPC2023 – Enhancement Mode Power Transistor

 $V_{DS}, 30\text{ V}$  $R_{DS(on)}, 1.45\text{ m}\Omega$  $I_D, 90\text{ A}$ 

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.



EPC2023 eGaN® FETs are supplied only in passivated die form with solder bumps. Die Size: 6.05 mm x 2.3 mm

Applications:

- High Frequency DC-DC Conversion
- Point-of-Load (POL) Converters
- Motor Drive
- Industrial Automation

Maximum Ratings			
PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	30	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	36	
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 6^\circ\text{C/W}$ )	90	A
	Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300\ \mu\text{s}$ )	590	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	°C
$T_{STG}$	Storage Temperature	-40 to 150	

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.4	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	1.1	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	42	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0\text{ V}$ , $I_D = 1.3\text{ mA}$	30			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0\text{ V}$ , $V_{DS} = 24\text{ V}$		0.1	1	mA
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5\text{ V}$		1	9	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4\text{ V}$		0.1	1	mA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 20\text{ mA}$	0.8	1.4	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5\text{ V}$ , $I_D = 40\text{ A}$		1.15	1.45	m $\Omega$
$V_{SD}$	Source-Drain Forward Voltage	$I_S = 0.5\text{ A}$ , $V_{GS} = 0\text{ V}$		1.5		V

All measurements were done with substrate connected to source.

Dynamic Characteristics (T<sub>j</sub> = 25°C unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C <sub>ISS</sub>	Input Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V		2150	2600	pF
C <sub>OSS</sub>	Output Capacitance			1530	2300	
C <sub>RSS</sub>	Reverse Transfer Capacitance			100		
C <sub>OSS(ER)</sub>	Effective Output Capacitance, Energy Related (Note 2)	V <sub>DS</sub> = 0 to 15 V, V <sub>GS</sub> = 0 V		1850		pF
C <sub>OSS(TR)</sub>	Effective Output Capacitance, Time Related (Note 3)			2020		
R <sub>G</sub>	Gate Resistance			0.3		Ω
Q <sub>G</sub>	Total Gate Charge	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 5 V, I <sub>D</sub> = 40 A		19	25	nC
Q <sub>GS</sub>	Gate-to-Source Charge	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 40 A		5.7		
Q <sub>GD</sub>	Gate-to-Drain Charge			3.2		
Q <sub>G(TH)</sub>	Gate Charge at Threshold			4		
Q <sub>OSS</sub>	Output Charge	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V		30	45	
Q <sub>RR</sub>	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

Note 2: C<sub>OSS(ER)</sub> is a fixed capacitance that gives the same stored energy as C<sub>OSS</sub> while V<sub>DS</sub> is rising from 0 to 50% BV<sub>DSS</sub>.

Note 3: C<sub>OSS(TR)</sub> is a fixed capacitance that gives the same charging time as C<sub>OSS</sub> while V<sub>DS</sub> is rising from 0 to 50% BV<sub>DSS</sub>.

Figure 1: Typical Output Characteristics at 25°C

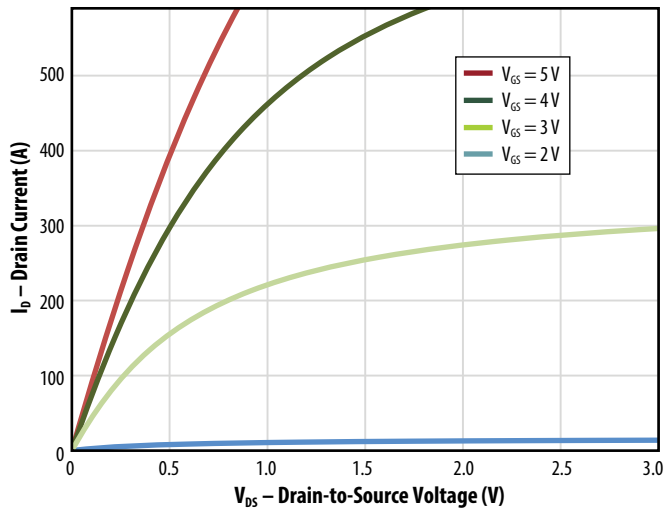


Figure 2: Transfer Characteristics

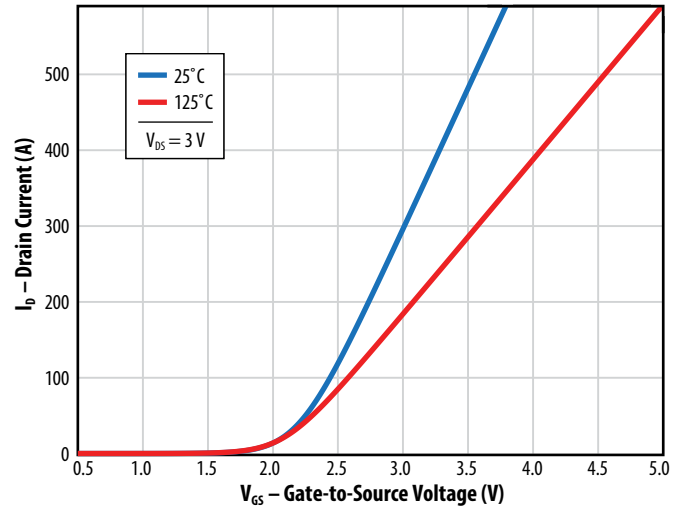


Figure 3: R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Drain Currents

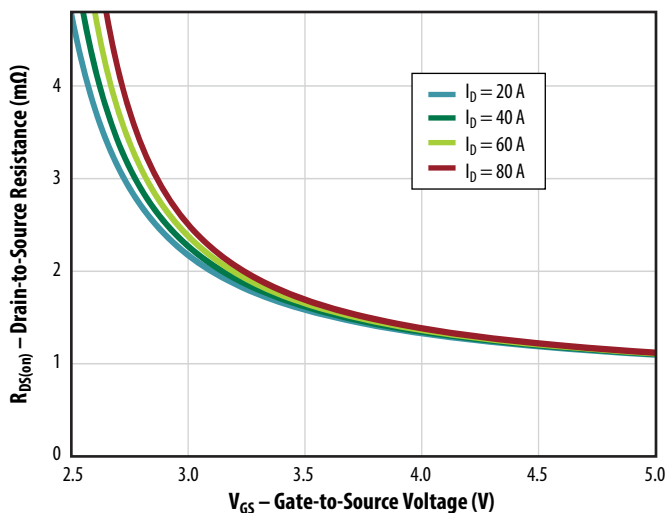


Figure 4: R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Temperatures

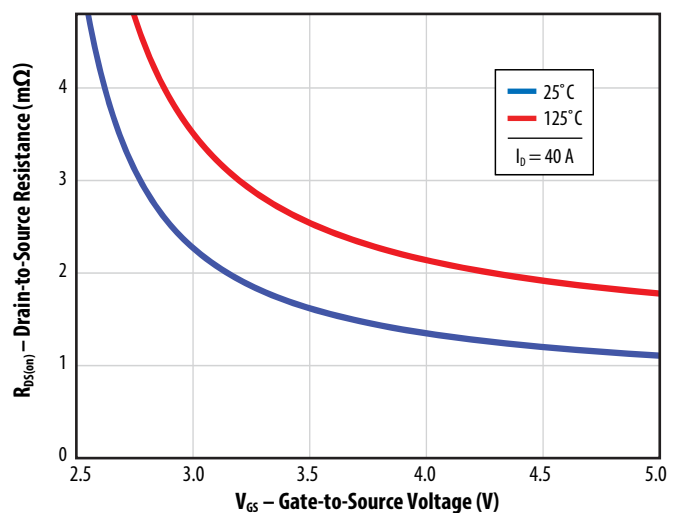


Figure 5a: Capacitance (Linear Scale)

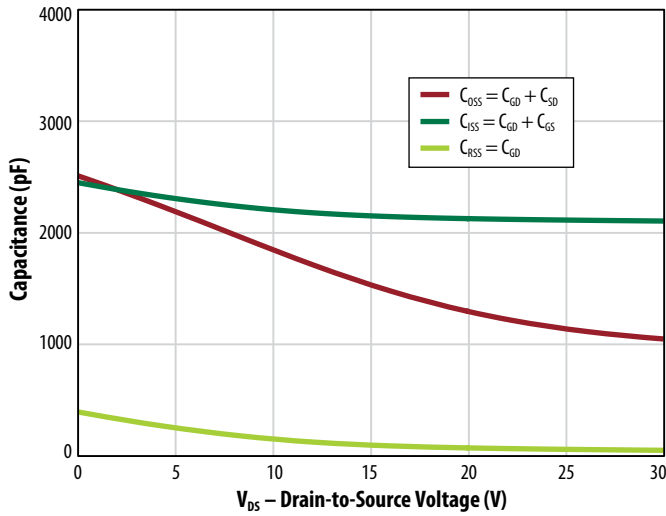


Figure 5b: Capacitance (Log Scale)

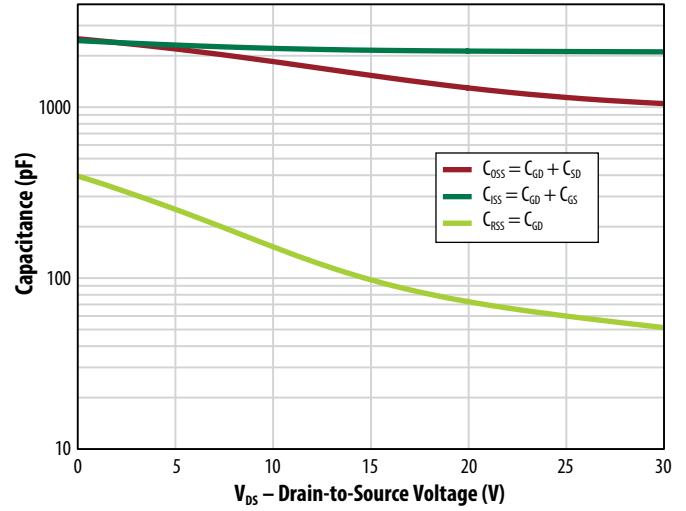


Figure 6: Output Charge and  $C_{OSS}$  Stored Energy

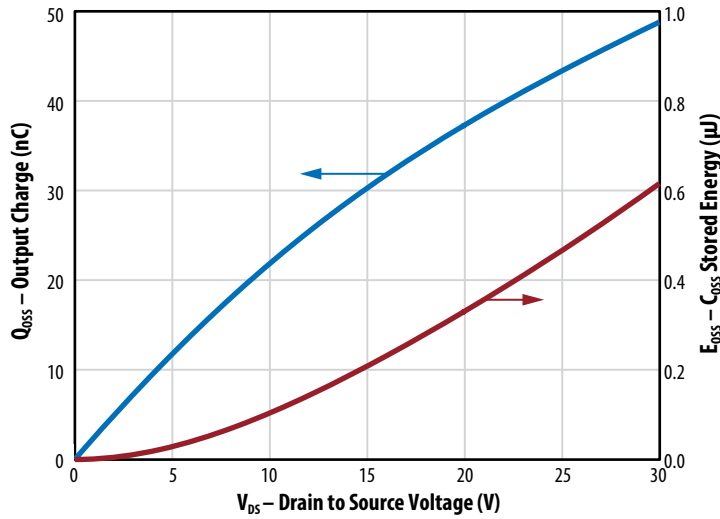


Figure 7: Gate Charge

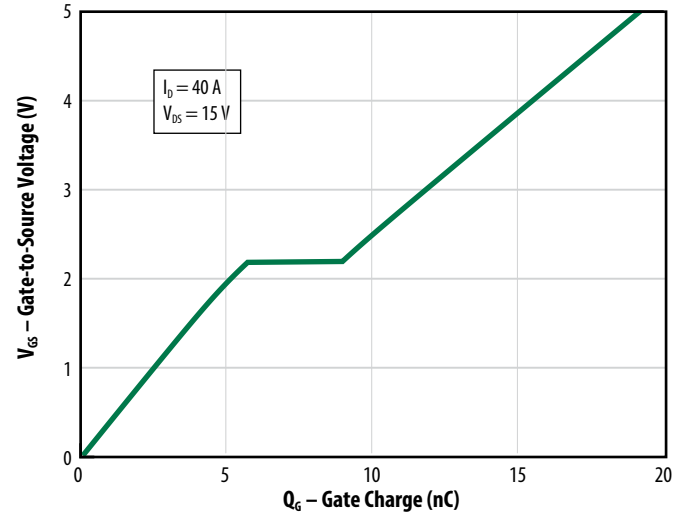


Figure 8: Reverse Drain-Source Characteristics

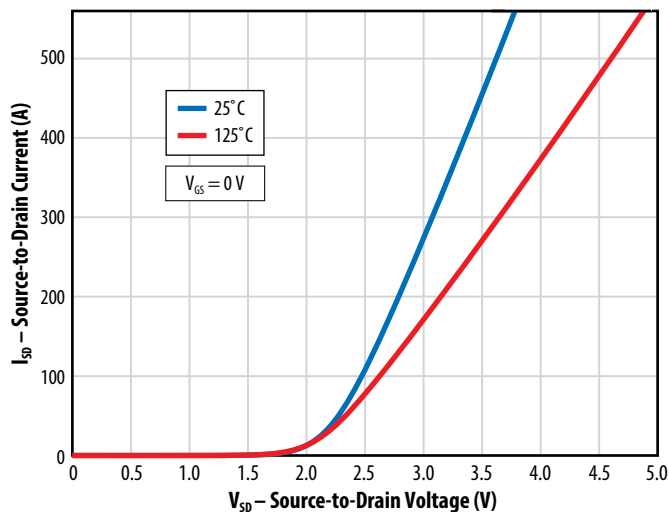
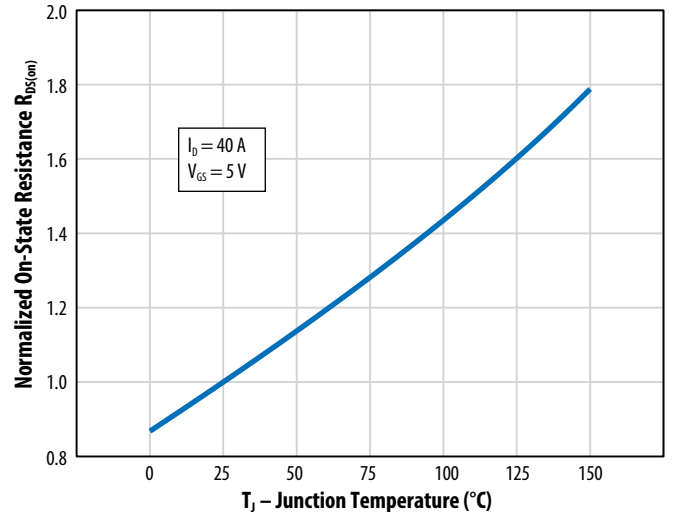


Figure 9: Normalized On-State Resistance vs. Temperature



All measurements were done with substrate shorted to source.

Figure 10: Normalized Threshold Voltage vs. Temperature

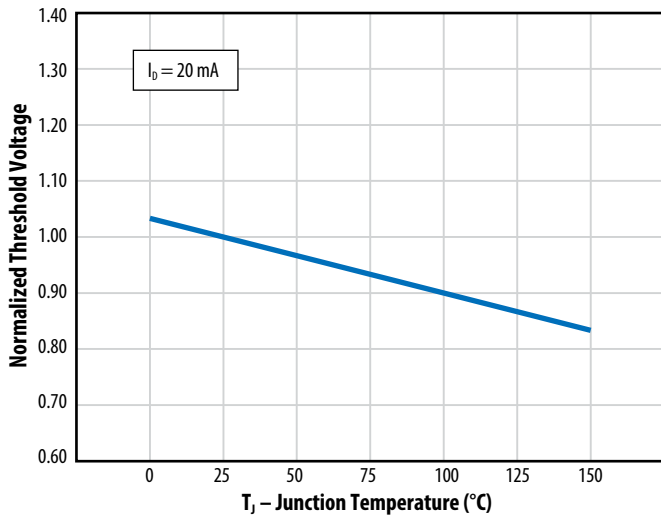


Figure 11: Safe Operating Area

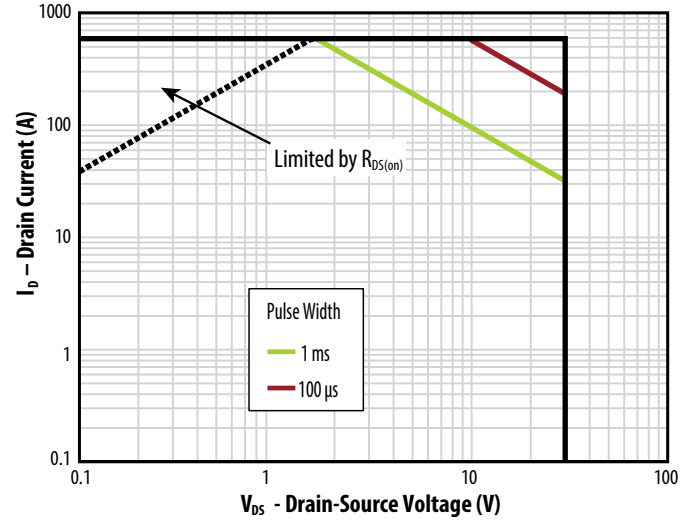
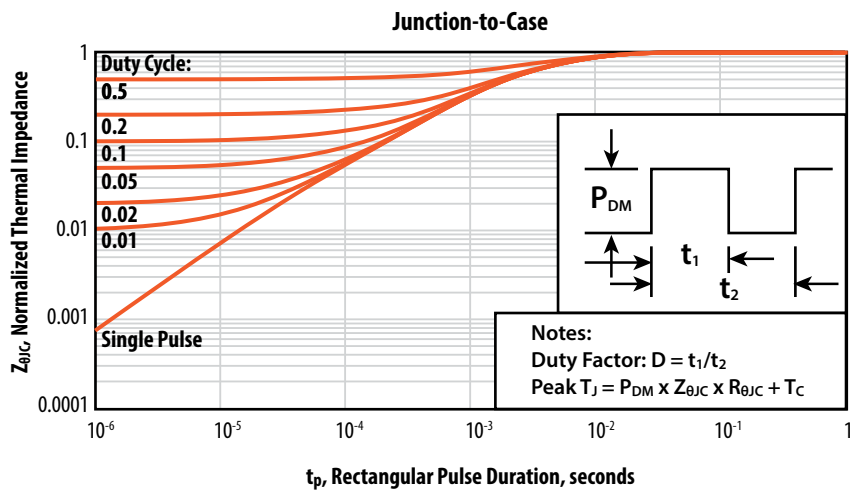
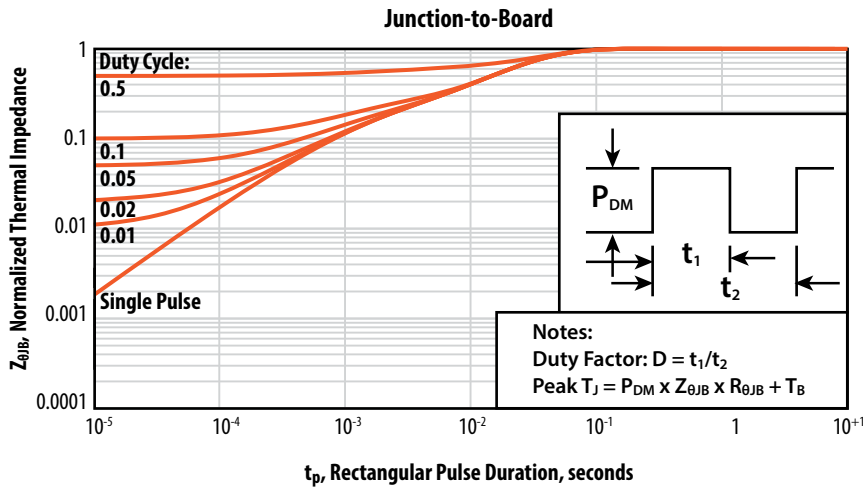
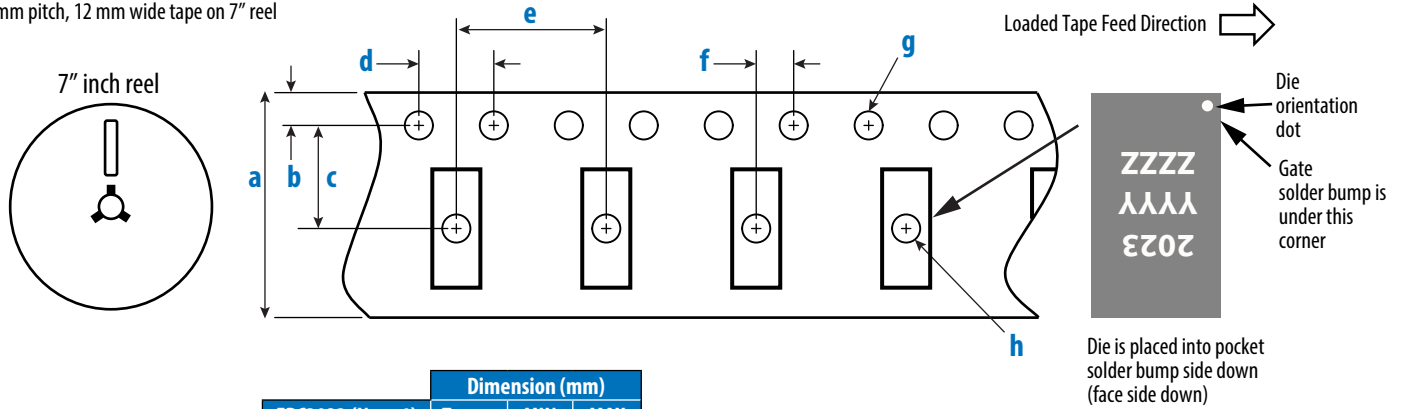


Figure 12: Transient Thermal Response Curves



**TAPE AND REEL CONFIGURATION**

8 mm pitch, 12 mm wide tape on 7" reel

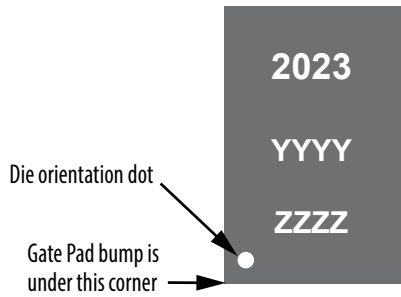


EPC2023 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	12.00	11.90	12.30
b	1.75	1.65	1.85
c (Note 2)	5.50	5.45	5.55
d	4.00	3.90	4.10
e	8.00	7.90	8.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60
h	1.50	1.50	1.75

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

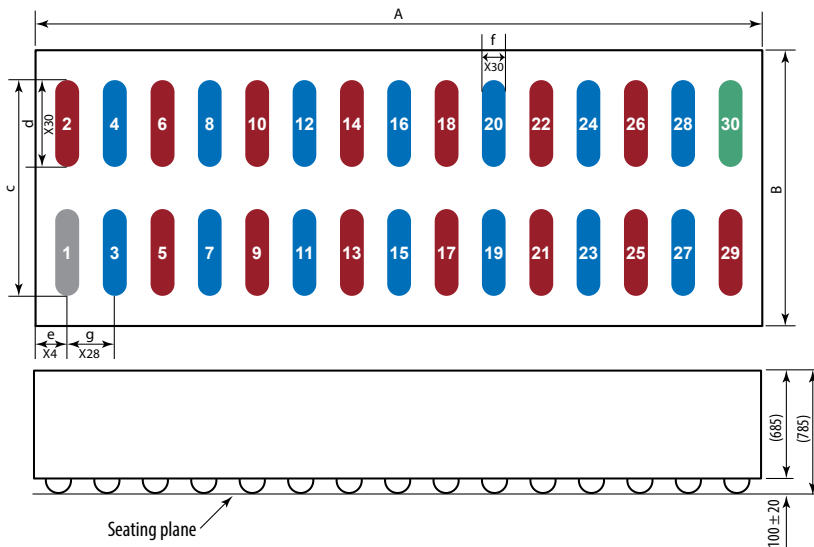
**DIE MARKINGS**



Part Number	Laser Markings		
	Part # Marking Line 1	Lot Date Code Marking Line 2	Lot Date Code Marking Line 3
EPC2023	2023	YYYY	ZZZZ

**DIE OUTLINE**

Solder Bump View



DIM	Micrometers		
	MIN	Nominal	MAX
A	6020	6050	6080
B	2270	2300	2330
c	2047	2050	2053
d	717	720	723
e	210	225	240
f	195	200	205
g	400	400	400

Pad 1 is Gate;

Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22,

25, 26, 29 are Source;

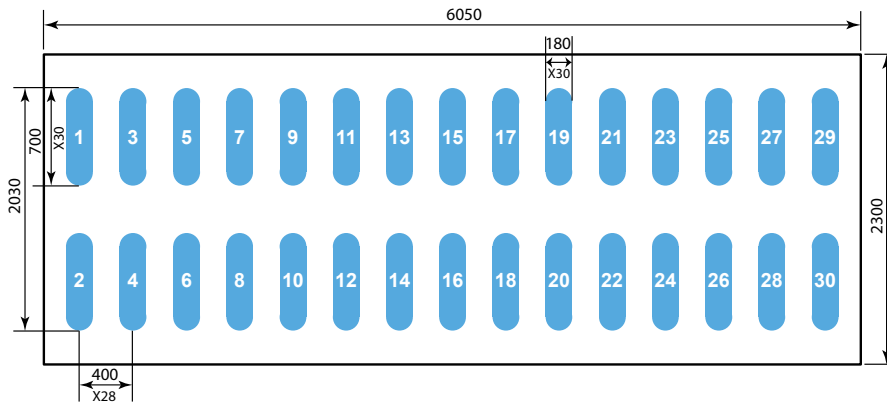
Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23,

24, 27, 28 are Drain;

Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED LAND PATTERN**  
(units in  $\mu\text{m}$ )

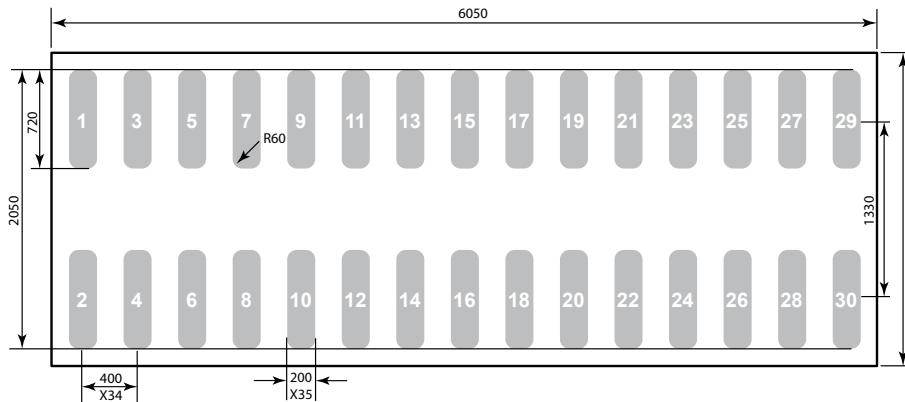


Land pattern is solder mask defined  
Solder mask opening is 180  $\mu\text{m}$   
It is recommended to have on-Cu trace PCB vias

Pad 1 is Gate;  
Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29 are Source;  
Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;  
Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED STENCIL DRAWING**  
(units in  $\mu\text{m}$ )



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 3 solder, reference 88.5% metals content.

Additional assembly resources available at <https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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Revised June, 2020